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Crystal structure solution via PED data: the BEA algorithm

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PED-Direct Methods

- Recently introduced *PED* techniques reduce the number of reflections which are simultaneously excited and therefore allow to describe the scattering by few beam approximations.
- Most of the statistical features of *PED* amplitudes are still unknown, with particular attention to the effects they produce on the efficiency of the phasing procedures, specifically on **Direct Methods** approaches, which so far are the most popular phasing techniques.

- A relatively large number of test cases is used.
- In our tests we use the amplitudes kindly provided by some friends (Gemmi, Mugnaioli, Kolb) for solving the structures: no attempt for improving them by techniques correcting for dynamical effects.
- As overall result, a number of recipes (among which the *BEA* algorithm) are obtained, which make the crystal structure solution *via PED* data more straightforward.

PED-ADT techniques

- Although *PED* techniques curtail the problem of dynamical diffraction, it is difficult to collect fully 3-dimensional data by them.
- Usually 2-dimensional reflections from few well oriented zone axis are collected.
- More recently the *ADT* technique has been developed which, in combination with *PED*, allows much larger completeness values. Five of our twelve test data were collected by combining *PED* with *ADT*.

Test structures

Code	SG	ASU	COLL	RES	NR _{0.9} /NR _{RES}	COMP (0.9/RES)
aker	P -4 2 ₁ m	O_{14} Mg ₂ Al ₆ Si ₄ Ca ₄	Р	0.40	83 / 339	53 / 23
Anatase	$I 4_1/a m d$	O ₈ Ti ₄	Р	0.25	25 / 267	81 / 22
Barite	P n m a	O ₁₆ S ₄ Ba ₄	P-A	0.77	225 / 355	83 / 82
Charo	P 2 ₁ /m	Ca ₂₄ K ₁₄ Na ₁₀ Si ₇₂ O ₁₈₆	P-A	1.18	2878 / 2878	97 / 97
gann	P 6 ₃ m c	Ga ₂ N ₂	Р	0.25	18 / 170	86/32
mayenite	I -4 3 d	$O_{88} Al_{28} Ca_{24}$	Р	0.54	100 / 228	83 / 44
mullite	P b a m	Al _{4.56} Si _{1.44} O _{9.72}	P-A	0.76	129 / 213	84 / 86
natrolite	Fdd2	$Na_2(Al_2 Si_3O_{10}) (H_2O)_2$	P-A	0.75	447 / 743	100 / 99
Sno2	P 4 ₂ /m n m	O ₄ Sn ₂	Р	0.29	26 / 212	72 / 24
Srtio3	P m -3 m	$O_3 \operatorname{Ti}_1 \operatorname{Sr}_1$	Р	0.26	16 / 180	84 / 43
srtio3_s	P b n m	$O_{12} Ca_{0.48} Sr_{3.52} Ti_4$	Р	0.26	47 / 464	25/6
zn8sb7	P -1	Zn ₃₂ Sb ₂₈	P-A	0.77	2679 / 3943	59 / 54

Data resolution

- *ED* reveals the electrostatic potential, which is the sum of nuclear and of electronic potentials: *viceversa*, the electrostatic potential around each atom influences the atomic scattering.
- The region substantially determining ED scattering amplitudes is wider than for XD: therefore the atomic scattering curve for ED more rapidly decreases with s than the corresponding X-ray curves.

Data Resolution

 In Fig. we show carbon and sulphur atomic scattering curves for e- and X-ray scattering: ED curves have been rescaled so that their maximum values are equal to Z. **Carbon** and **sulphur** atomic scattering curves versus RES for *XD* (blue lines) and, after rescaling, for *ED* (red lines)



The more rapid decay of the electron scattering may suggest that *ED* data should be detectable only at resolution smaller than for X-rays. This effect however is contrasted by the stronger electron scattering (1000 times about) than X-rays, but is strengthened by the smaller size of the crystal samples submitted to electron diffraction.

As a first conclusion, *PED* data can really attain quite high resolution as effect of three sample parameters (electrostatic potentials, strength of the scattering, size of the crystal) and of the shorter wavelength (much shorter than for X-rays): their data quality *versus* the resolution, however, has still to be assessed. c

Data Resolution

- In conclusion, the shorter electron wavelength combined with *PED* techniques allows to collect data at very high resolution, but their measurement errors are expected to be particularly large.
- However we will show below that such reflections may be useful in the phasing process, and contribute to make the structural model more complete.

Data completeness

- COMP=data completeness=number of measured / number of measurable reflections, at RES and at 0.9 Å resolution.
- NR= corresponding number of symmetry independent reflections.
- COMP is quite unsatisfactory when the nominal RES value is smaller than 0.4 Å: in particular data collected by combining PED and ADT show lower resolution but better data completeness, so providing a better basis for accurate crystal structure refinement.

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mullite	P b a m	Al _{4.56} Si _{1.44} O _{9.72}	P-A	0.76	129 / 213	84 / 86
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Data Quality

Indications on the data quality may be obtained by the internal R-value

$$R_{\rm int} = \frac{\sum |F_{obs} - \langle F_{obs} \rangle|}{\sum |F_{obs}|}$$

The sum is over symmetry equivalent reflections.

Since X-Ray structures are known the kinematical data quality may be estimated via

$$RESID = \frac{\sum |F_{obs} - F_{calc}|}{\sum |F_{obs}|}$$

The sum is over the measured reflections

Code	R_{int} (∞ -0.9)	R _{int} (0.9-RES)	RESID _{RES}	RESID _{0.9}
aker	6.3	14.5	35.7	25.3
anatase	7.6	18.8	48.9	30.2
barite	14.6	18.2	33.4	32.3
charo	13.3			
gann	1.9	5.7	28.5	20.7
mayenite	20.5	27.6	40.8	34.2
mullite	29.4	40.5	36.3	34.4
natrolite	19.2	26.8	25.8	23.7
sno2			36.9	26.4
srtio3	18.5	18.9	40.7	19.2
srtio3_s	15.8	13.1	58.4	46.3
zn8sb7	16.1	24.4		

Direct Methods (DM)

- 200 trials were run for each test structure by using Sir2008 (Version 3.0), included in the package II Milione.
- **DM** section is automatically followed by a direct space procedure which, *via* **EDM** techniques and diagonal **LSQ**, tries to improve **DM** models.
- **RESID** is used as a **FOM** for recognizing the correct solution. All the following results are referred to the best solution found within the five trials with the lowest values of **RESID**.

Protocols

- We used three different protocols.
- **Protocol 1**. All the measured data up to RES are used in the phasing process.
- Protocol 2. Only data up to 0.7 Å resolution were used in the phasing process
- Protocol 3. Only data up to 0.9 Å resolution were used in the phasing process.
- The results are in the figure

Model quality

- The analysis of the results suggests that:
- the structure models obtained by Prot.1 are more complete than those obtained by Prot.2, which are more complete than those obtained by Prot. 3.
- This behavior may be related to the recent use of the extrapolation techniques in protein structure determination, where phases and amplitudes of non-measured (because out of the measured reciprocal space) reflections are estimated via probabilistic approaches and used during the phase determination process.



Model quality

- The *RESID* values available at the end of the automatic phasing process (where peaks are labeled, and thermal factors are still isotropic) are shown in the next Fig. . Obviously they are larger for Prot.1 than for Prot.2 than for Prot.3.
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- Most of the RESID values are far from the values obtained by *Sir2008* for X-ray data (usually between 0.08 and 0.12).

About the BEA algorithm

- If **PED** techniques are used, the dynamical effects are no more dominant but still present.
- Two questions arise:
- 1) Is the average (over symmetry equivalent reflections) a good representative of the correct intensity?
 A: yes and no
- 2)In absence of a theoretical formulation establishing which of the equivalent reflections is less affected by dynamical scattering, can one use a practical criterion for selecting the *best* unique reflection?

The BEA algorithm

- BEA suggests to choose as unique reflection that one which better agrees with the current structural model.
- The effect is certainly cosmetic (the final *RESID* value may be much smaller than that obtained by using the average of the equivalent amplitudes). But it may also be substantial: i.e., the crystal structure solution becomes more straightforward and the final structural model may be more complete. We call this algorithm **BEA** (best equivalent amplitude).

The BEA algorithm

- BEA has some similarity with a criterion used in powder crystallography during the phasing process.
- When a structural model is not available the experimental diffraction profile is decomposed according to LeBail or to Pawley algorithms.
- If a structural model is available, the experimental diffraction profile is partitioned in a way proportional to the calculated structure factors of the overlapping reflections.

The BEA procedure

- When Direct Methods are run, the average amplitude of the symmetry equivalent reflections is used (no structural model is available at this stage).
- As soon as a model is available, the *best* equivalent reflection may be recognized and the corresponding amplitude is used as coefficient of the observed Fourier maps and as observed amplitude in the diagonal least-squares automatically performed by *Sir2008*.
- Obviously the best reflection changes with the structural model.

 In the ED case BEA recognizes that uncorrected dynamical effects still affect the experimental data (even in the PED case), that such effects are not corrected by a posteriori techniques, and that the merging of the symmetry equivalent reflections may lead to averaged values which are not good representatives of the true intensities.

Check BEA

- To check **BEA** we used the following three protocols.
- *Prot. 4.* All the measured data up to *RES* are used in the phasing process (as in Protocol 1), and *BEA* is used.
- *Prot. 5.* Only data up to 0.7 Å resolution were used in the phasing process (as in Protocol 2), and *BEA* is applied.
- *Prot. 6*. Only data up to 0.9 Å resolution were used (as in Protocol 3) and *BEA* is applied.

- Compare the results attained via Protocols 4,5,6 with those obtained via Protocols 1,2,3 respectively (compare protocol i and i+3, because they imply the same data resolution).
- We observe that the use of *BEA*:
- A)usually leads to more complete structural models.
- B)may strongly improve the *RESID* values, particularly when the nominal data resolution is high, and makes them very close to the X-ray values usually obtained at this stage of refinement.

Efficiency of Prots. 1 and 4

- Prot. 1- Sir2008 is able to find a complete solution in all the cases except for anatase (one O and one Ti atom in the asymmetric: Ti was missed), barite (4 atoms over 5 well located: one O was missed), mullite (one O missed), srtio3_s (Ti and Ca-Sr atoms were missed).
- Prot 4- All the atomic positions of the test structures were found, but for *mullite*, for which one O with chemical occupancy equal to 0.14 was missed.

Advantages of BEA

- It usually leads to more complete structural models.
- It may strongly improve the RESID values, particularly when the nominal data resolution is high, and makes them very close to the values usually obtained for X-ray data at this stage of refinement.
- More extended applications are needed to extrapolate the usefulness of *BEA* for the final refinement stages.

